

# CA-1000 Silicon Photonics Chip Auto-Alignment System

ETSC Sip-Chip/Bar automatic test system covers a variety of chips, including passive and active chips. The system uses required instruments to test chip performance indexes, such as IL, ER, RL FSR, Responsivity, etc. Vision algorithm can realize automatic optical-alignment and probe card contact with pad, without human beings' participation.

The coupling mode includes Grating-Coupler and Edge-Coupler. Response mode could either be optical feedback (power meter) or electric feedback (source meter). Optical-mode the system supports is at least 1.5um, if need be, replacement of motor type can support smaller mode chip test.



		X, Y, Z	$\theta X, \theta Y, \theta Z$
Coupling Stage	Travel range	$\geq 30$ mm	$\geq 8$ deg
	Resolution	$\leq 50$ nm	$\leq 0.003$ deg
	Repeatability	$\leq 1$ $\mu$ m	$\leq 0.02$ deg
Optical-align time		<10s for single fiber	
		<1 min for fiber array	
Optical-align repeatability		SMF-SiPh variation < 0.2 dB	
Stability		15min < 0.5 dB	
User-Case		2 SMF-Edge coupler; 2 SMF-Grating coupler; 1 1x4 FA-Edge coupler; 1 1x8 FA-Grating coupler; Response: Power or PD.	

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